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Joint ICTP-IAEA Advanced Workshop on High Sensitivity 2D & 3D Characterisation and Imaging with Ion Beams | (smr 2856)

Thursday 29 September 2016

DAY 4 - LB (Euler Lecture Hall) (08:30-17:30)

time	title	presenter
08:30	Depth profiling and 3D tomography for 3D RBS such as Corteo, Maria, and for calculation of depth resolution	BARRADAS, Nuno P.
09:30	State of the art codes to affect the IBA analysis	CALLIGARO, Thomas
10:30	Coffee break	
11:00	Radiation damage during analysis	WEBB, Roger
12:00	Case study (I) - Materials science	BARRADAS, Nuno P.
13:00	Lunch break	
14:30	PowerMeis software	GRANDE, Pedro L.
15:30	Comparison of External Ion Imaging Techniques with Alternative Techniques	CALLIGARO, Thomas
16:30	Coffee break	
16:30	IBA-clinic	WEBB, Roger AND ALL LECTURERS